Silicon Wafer Europe TC Chapter

SEMICON Europe Standards Meetings
Thursday, Nov 20, 2025
11:00 AM - 1:00 PM CET
ICM/Office Staffelsee

AGENDA

1.0 Welcome / Call to Order

- 1.1 Introductions
- 1.2 Meeting Reminders *(Membership Requirement, Antitrust and Intellectual Property Reminders, Effective Meeting Guidelines)*
- 1.3 Agenda Review

2.0 Review and Approval of Previous Meeting Minutes

3.0 Liaison Report

- 3.1 Japan Committee
- 3.2 North America

4.0 Staff Report

5.0 Ballot Review

- 5.1 Doc. 6983A - Revision to SEMI M49-0918 With Title Change To: Guide for Specifying Geometry Measurement Systems for Silicon Wafers for the 130 nm To 3 nm Technology Generations

6.0 Task Force Reports

- **6.1** Int'l Advanced Wafer Geometry Task Force /F. Riedel/F. Passek
- **6.2** Int'l Automated Advanced Surface Inspection Task Force/ J. Wittmann
- **6.3** Int'l Polished Wafer Task Force/ C. Sanna
- **6.4** Int'l Test Methods TF/T. Hager

7.0 Old Business

8.0 New Business

9.0 Action Item Review

- 9.1 Open Action Items
- 9.2 New Action Items

10.0 Next Meeting and Adjournment